

1. (Twice Amended) A method of identifying a plurality of substantially identical integrated circuits formed on a common substrate, comprising the steps of:

programming each of the integrated circuits with respective electronic identification information distinguishing the integrated circuits from one another; and

marking each of the integrated circuits with respective optical identification code which corresponds with the respective electronic identification information[.];

reading the optical identification code on each of the integrated circuits; and

associating the optical identification code on each of the integrated circuits with the corresponding electronic identification information.

3. (Twice Amended) The method of claim [2]¹ wherein the step of associating the optical identification code on each of the integrated circuits with the corresponding electronic identification information includes the step of accessing a look-up table.

7. (Twice Amended) In a plurality of substantially identical integrated circuits formed on a common substrate, each of the integrated circuits including a programmable circuit for storing respective electronically readable identification code which distinguishes the integrated circuits from one another, a method of identifying the integrated circuits, comprising the steps of:

marking each of the integrated circuits with respective optical identification code; [and]

associating the optical identification code on each of the integrated circuits with the respective electronically readable identification code[.] and

reading the optical identification code on each of the integrated circuits.

11. (Twice Amended) A wafer comprising a plurality of dies, each die including an integrated circuit having a programmable identification circuit that stores identification data, and each die having an optical identification mark positioned thereon and encoding information corresponding to the identification data, the optical identification mark on each die corresponding to the electronic identification information.

22. (Amended) A method of identifying a plurality of substantially identical integrated circuits formed on a common substrate, each of the integrated circuits being formed on a respective one of a plurality of substrate dies, the method comprising:

programming each of the plurality of integrated circuits with respective electronic identification information for each of the integrated circuits; and

marking each of the dies with optical identification code which corresponds with the respective electronic identification information[.];

reading the optical identification code on each of the integrated circuits;

reading the electronic identification information from each of the integrated circuits; and

associating the optical identification code on each of the integrated circuits with the corresponding electronic identification information.

REMARKS

This is in response to a series of telephone interviews with Examiner St-Cyr and Hajec concerning the Office Action of February 25, 1999. The time and courtesy of the Examiners' in conducting these interviews are much appreciated by Applicant. During these interviews, applicant's attorney explained